

TECHNICAL SPECIFICATIONS

Optical

	PDM+	PDM+ HP	PDM ₄₊	PDM ₄₊ HP
Peak power	Up to 2W	Up to 3.2W	Up to 7W	Up to 10W
Pulse width	From 2ns to CW	From 4ns to CW	From 2ns to CW	From 4ns to CW
Repetition rate	From single-shot to 250 MHz		From single-shot to 250 MHz	
Available wavelengths (nm)	808, 976, 1030, 1064, 1075 ⁽¹⁾		976, 1064, 808 ⁽²⁾	
Operating mode	Pulsed and CW		Pulsed and CW	
Beam quality	Single-mode		Single-mode	
Command interface	TTL/LVTTL ⁽³⁾		TTL/LVTTL ⁽³⁾	
Output fiber	SM/PM		SM/PM	

(1) Other available wavelengths: 845, 1310, 1480, 1550 nm...

(2) Choose two wavelengths from 976, 1064, 808 nm...

(3) LVDS or other on demand (LVPECL, CML, LVS)

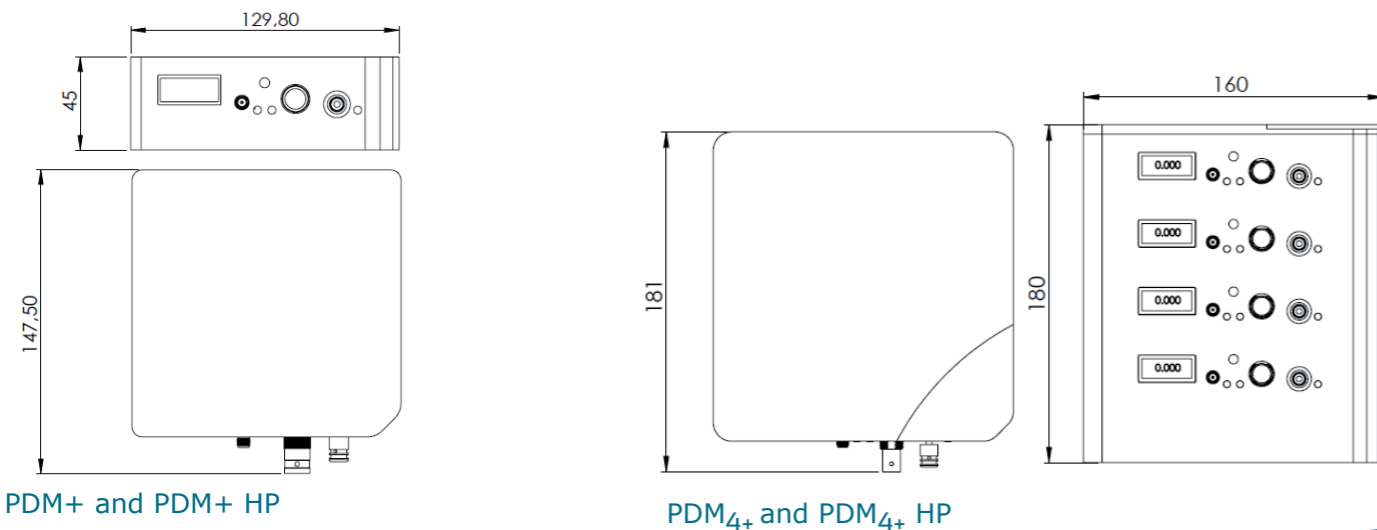
Options

- Polarized fiber (single-mode only)
- Output isolator
- Narrow emission bandwidth
- Separated collimator
- Interlock
- Various fiber connectors (FC, SMA...)

Electrical

Operating voltage	12-15 Vdc (OEM) 110/220V ac/dc converter included
Input impedance	50 Ω

Mechanical



Photos: ALPhANOV



PULSE-ON-DEMAND MODULES

PDM SERIES

PULSE-ON-DEMAND MODULES

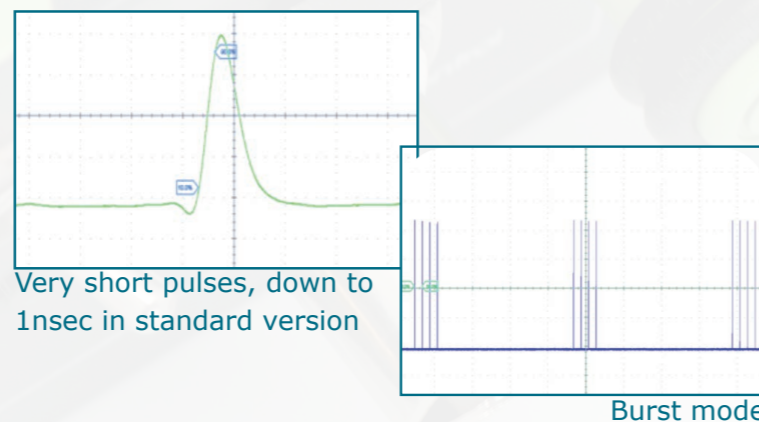
FOR FULL TEMPORAL AGILITY

Generate optical pulses on demand from input TTL/LVTTL digital signal with extremely low jitter

PDM+



Up to **3.2W** peak power with single-mode output signal



PDM 4+



Up to **10.5W** peak power with single-mode output signal

The PDM series consists of OEM laser modules which generate optical pulses from input TTL/LVTTL digital signal. From single-shot to continuous wave (CW), with pulse length from 2ns to any required pulse-burst configuration, the PDM series offers the best temporal flexibility on the laser market.

Key features:

- Single-shot, burst mode or CW operation
- Up to 10.5W peak power
- Min. pulse duration: 2 nsec (FWHM)
- Extremely low jitter (<8ps)
- Large range of wavelengths from UV to IR
- Up to 250 MHz repetition rate
- Excellent beam quality
- Generate short pulses from a longer TTL signal
- Smart control (USB interface)

Key applications:

- MOPA architecture
- Low power micromachining
- Laser development
- Non destructive control
- Telemetry
- Doppler measurements
- Metrology
- Semiconductor testing